

(b) (5) DPP, (b) (7)(C), (b) (7)(D)

Mark K. Han

3767

SEARCHED			
Class	Subclass	Date	Examiner
604	22 93.01	7/23/2006	malh
	164.01		
	164.02		
	164.03		
	164.05		
	164.06		
	164.07		
	164.08		
	164.12		
	167.01		
	167.02		
	167.03		
	167.04		
	170.01		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

[illegible]

Search Notes (continued)

Application/Control No.

10/092,560

Examiner

Mark K. Han

Applicant(s)/Patent under
Reexamination

BLANCO, ERNESTO E.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner
604	170.02	7/23/2006	msh

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR